

Search Notes

Application/Control No.

10/652,269

Examiner

Erin D. Chiem

Applicant(s)/Patent under
Reexamination

ZHOU ET AL.

Art Unit

2883

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted Kaveh Kianni	11/22/2005	EDC
359/652.ccls. and layer same thickness same (wavelength wave adj length)	11/22/2005	EDC
(graded gradient) near5 (index indice) same taper\$3 near3 waveguide and 21 and layer same thickness	11/22/2005	EDC